

# VND810PEP-E

TARGET SPECIFICATION

# DOUBLE CHANNEL HIGH SIDE DRIVER

#### **Table 1. General Features**

TYPE	R <sub>DS(on)</sub>	Ιουτ	Vcc
VND810PEP-E	160 mΩ (*)	3.5 A (*)	36 V

(\*) Per each channel

- CMOS COMPATIBLE INPUTS
- OPEN DRAIN STATUS OUTPUTS
- ON STATE OPEN LOAD DETECTION
- OFF STATE OPEN LOAD DETECTION
- SHORTED LOAD PROTECTION
- UNDERVOLTAGE AND OVERVOLTAGE SHUTDOWN
- PROTECTION AGAINST LOSS OF GROUND
- VERY LOW STAND-BY CURRENT
- REVERSE BATTERY PROTECTION (\*\*)
- IN COMPLIANCE WITH THE 2002/95/EC EUROPEAN DIRECTIVE

### DESCRIPTION

The VND810PEP-E is a monolithic device designed in STMicroelectronics VIPower M0-3 Technology, intended for driving any kind of load with one side connected to ground.

Active  $V_{CC}$  pin voltage clamp protects the device against low energy spikes (see ISO7637 transient compatibility table).

#### Figure 1. Package



Active current limitation combined with thermal shutdown and automatic restart protects the device against overload. The device detects open load condition both in on and off state. Output shorted to  $V_{CC}$  is detected in the off state. Device automatically turns off in case of ground pin disconnection.

#### **Table 2. Order Codes**

Package	Tube	Tape and Reel
PowerSSO-12	VND810PEP-E	VND810PEPTR-E

Note: (\*\*) See application schematic at page 9

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#### Figure 2. Block Diagram



### **Table 3. Absolute Maximum Ratings**

Symbol	Parameter	Value	Unit
Vcc	DC Supply Voltage	41	V
- V <sub>CC</sub>	Reverse DC Supply Voltage	- 0.3	V
- I <sub>GND</sub>	DC Reverse Ground Pin Current	- 200	mA
IOUT	DC Output Current	Internally Limited	А
- I <sub>OUT</sub>	Reverse DC Output Current	- 6	А
I <sub>IN</sub>	DC Input Current	+/- 10	mA
I <sub>stat</sub>	DC Status Current	+/- 10	mA
V <sub>ESD</sub>	Electrostatic Discharge (Human Body Model: R=1.5KΩ; C=100pF) - INPUT - STATUS - OUTPUT - V <sub>CC</sub>	4000 4000 5000 5000	V V V V
P <sub>tot</sub>	Power Dissipation T <sub>C</sub> =25°C	54	W
Тj	Junction Operating Temperature	Internally Limited	°C
Tc	Case Operating Temperature	- 40 to 150	°C
T <sub>stg</sub>	Storage Temperature	- 55 to 150	°C





#### Figure 4. Current and Voltage Conventions



#### Table 4. Thermal Data

Symbol	Parameter		Value		Unit
R <sub>thj-case</sub>	Thermal resistance junction-case	(MAX)	2.3		°C/W
R <sub>thj-amb</sub>	Thermal resistance junction-ambient	(MAX)	61 (*)	50 (**)	°C/W

Note: (\*) When mounted on a standard single-sided FR-4 board with  $1 \text{cm}^2$  of Cu (at least  $35\mu\text{m}$  thick) connected to all V<sub>CC</sub> pins. Note: (\*\*) When mounted on a standard single-sided FR-4 board with  $8 \text{cm}^2$  of Cu (at least  $35\mu\text{m}$  thick) connected to all V<sub>CC</sub> pins.

## **ELECTRICAL CHARACTERISTICS** (8V<V<sub>CC</sub><36V; -40°C<T<sub>j</sub><150°C unless otherwise specified)

(Per each channel)

## Table 5. Power Outputs

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
V <sub>CC</sub>	Operating Supply Voltage		5.5	13	36	V
V <sub>USD</sub>	Undervoltage Shut-down		3	4	5.5	V
Vov	Overvoltage Shut-down		36			V
Ron	On State Resistance	I <sub>OUT</sub> =1A; T <sub>j</sub> =25°C			160	mΩ
NON	On State Resistance	I <sub>OUT</sub> =1A; V <sub>CC</sub> >8V			320	mΩ
		Off State; V <sub>CC</sub> =13V; V <sub>IN</sub> =V <sub>OUT</sub> =0V		12	40	μA
IS	Supply Current	Off State; V <sub>CC</sub> =13V; V <sub>IN</sub> =V <sub>OUT</sub> =0V; T <sub>j</sub> =25°C		12	25	μA
		On State; $V_{CC}$ =13V; $V_{IN}$ =5V; $I_{OUT}$ =0A		5	7	mA
I <sub>L(off1)</sub>	Off State Output Current	V <sub>IN</sub> =V <sub>OUT</sub> =0V	0		50	μΑ
I <sub>L(off2)</sub>	Off State Output Current	V <sub>IN</sub> =0V; V <sub>OUT</sub> =3.5V	-75		0	μΑ
I <sub>L(off3)</sub>	Off State Output Current	$V_{IN}=V_{OUT}=0V$ ; $V_{CC}=13V$ ; $T_j=125$ °C			5	μΑ
I <sub>L(off4)</sub>	Off State Output Current	$V_{IN}=V_{OUT}=0V$ ; $V_{CC}=13V$ ; $T_j=25^{\circ}C$			3	μΑ

## Table 6. Switching (V<sub>CC</sub> =13V)

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
t <sub>d(on)</sub>	Turn-on delay time	$R_L=13\Omega$ from $V_{IN}$ rising edge to $V_{OUT}=1.3V$		30		μs
t <sub>d(off)</sub>	Turn-on delay time	$R_L=13\Omega$ from $V_{IN}$ falling edge to $V_{OUT}=11.7V$		30		μs
(dV <sub>OUT</sub> / dt) <sub>on</sub>	Turn-on voltage slope	$R_L$ =13 $\Omega$ from V_OUT=1.3V to V_OUT=10.4V		See relative diagram		V/µs
(dV <sub>OUT</sub> / dt) <sub>off</sub>	Turn-off voltage slope	$R_L=13\Omega$ from $V_{OUT}=11.7V$ to $V_{OUT}=1.3V$		See relative diagram		V/µs

## Table 7. V<sub>CC</sub> - Output Diode

ſ	Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
	VF	Forward on Voltage	-I <sub>OUT</sub> =0.5A; T <sub>j</sub> =150°C			0.6	V

#### Table 8. Status Pin

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
V <sub>STAT</sub>	Status Low Output	I <sub>STAT</sub> = 1.6 mA			0.5	V
VSIAI	Voltage				0.0	v
I <sub>LSTAT</sub>	Status Leakage Current	Normal Operation; V <sub>STAT</sub> = 5V			10	μΑ
C <sub>STAT</sub>	Status Pin Input Capacitance	Normal Operation; V <sub>STAT</sub> = 5V			100	pF
Vee	Status Clamp Voltage	I <sub>STAT</sub> = 1mA	6	6.8	8	V
V <sub>SCL</sub>	Status Clamp Voltage	I <sub>STAT</sub> = - 1mA		-0.7		V

#### ELECTRICAL CHARACTERISTICS (continued)

#### Table 9. Logic Input

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
VIL	Input Low Level				1.25	V
Ι <sub>ΙL</sub>	Low Level Input Current	V <sub>IN</sub> = 1.25V	1			μΑ
VIH	Input High Level		3.25			V
I <sub>IH</sub>	High Level Input Current	V <sub>IN</sub> = 3.25V			10	μΑ
V <sub>I(hyst)</sub>	Input Hysteresis Voltage		0.5			V
V <sub>ICL</sub>	Input Clamp Voltage	I <sub>IN</sub> = 1mA I <sub>IN</sub> = -1mA	6	6.8 -0.7	8	V V
		$\eta_N = -100A$		-0.7		v

#### Table 10. Protections (See note 1)

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
T <sub>TSD</sub>	Shut-down Temperature		150	175	200	°C
T <sub>R</sub>	Reset Temperature		135			°C
T <sub>hyst</sub>	Thermal Hysteresis		7	15		°C
t <sub>SDL</sub>	Status Delay in Overload Conditions	T <sub>j</sub> >T <sub>TSD</sub>			20	μs
l.	Current limitation		3.5	5	7.5	А
l <sub>lim</sub>	Current initiation	5.5V <v<sub>CC&lt;36V</v<sub>			7.5	А
V <sub>demag</sub>	Turn-off Output Clamp Voltage	I <sub>OUT</sub> =1A; L=6mH	V <sub>CC</sub> -41	V <sub>CC</sub> -48	V <sub>CC</sub> -55	V

Note: 1. To ensure long term reliability under heavy overload or short circuit conditions, protection and related diagnostic signals must be used together with a proper software strategy. If the device is subjected to abnormal conditions, this software must limit the duration and number of activation cycles.

#### Table 11. Openload Detection

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
la	Openload ON State	V <sub>IN</sub> =5V	20	40	80	mA
IOL	Detection Threshold	VIN=5 V	20	40	00	IIIA
<b>+</b>	Openload ON State	1 00			200	
t <sub>DOL(on)</sub>	Detection Delay	I <sub>OUT</sub> =0A			200	μs
V <sub>OL</sub>	Openload OFF State Voltage Detection Threshold	V <sub>IN</sub> =0V	1.5	2.5	3.5	V
t <sub>DOL(off)</sub>	Openload Detection Delay at Turn Off				1000	μs

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### Figure 5.



## Figure 6. Switching time Waveforms



CONDITIONS	INPUTn	OUTPUT <sub>n</sub>	STATUS <sub>n</sub>
Normal Operation	L	L	H
	H	H	H
Current Limitation	L	L	H
	H	X	(T <sub>j</sub> < T <sub>TSD</sub> ) H
	H	X	(T <sub>j</sub> > T <sub>TSD</sub> ) L
Overtemperature	L H	L	H L
Undervoltage	L H	L	X X
Overvoltage	L H	L	H H
Output Voltage > V <sub>OLn</sub>	L	H	L
	H	H	H
Output Current < I <sub>OLn</sub>	L	L	H
	H	H	L

#### Table 12. Truth Table

## Table 13. Electrical Transient Requirements on $V_{\mbox{CC}}$ Pin

ISO T/R 7637/1 Test Pulse	TEST LEVELS				
	I	П	III	IV	Delays and Impedance
1	-25 V	-50 V	-75 V	-100 V	2 ms 10 Ω
2	+25 V	+50 V	+75 V	+100 V	0.2 ms 10 Ω
3a	-25 V	-50 V	-100 V	-150 V	0.1 μs 50 Ω
3b	+25 V	+50 V	+75 V	+100 V	0.1 μs 50 Ω
4	-4 V	-5 V	-6 V	-7 V	100 ms, 0.01 Ω
5	+26.5 V	+46.5 V	+66.5 V	+86.5 V	400 ms, 2 Ω

ISO T/R 7637/1 Test Pulse	TEST LEVELS RESULTS			
	l	II	III	IV
1	С	С	С	С
2	С	С	С	С
3a	С	С	С	С
3b	С	С	С	С
4	С	С	С	С
5	С	E	E	E

CLASS	CONTENTS
С	All functions of the device are performed as designed after exposure to disturbance.
E	One or more functions of the device is not performed as designed after exposure to disturbance and cannot be returned to proper operation without replacing the device.

\_\_\_\_\_

#### Figure 7. Waveforms



#### **Figure 8. Application Schematic**



# GND PROTECTION NETWORK AGAINST REVERSE BATTERY

<u>Solution 1:</u> Resistor in the ground line ( $R_{GND}$  only). This can be used with any type of load.

The following is an indication on how to dimension the  $R_{\mbox{\scriptsize GND}}$  resistor.

1)  $R_{GND} \le 600 \text{mV} / (I_{S(on)max})$ .

2)  $R_{GND} \ge (-V_{CC}) / (-I_{GND})$ 

where  $\mathsf{-I}_{\text{GND}}$  is the DC reverse ground pin current and can be found in the absolute maximum rating section of the device's datasheet.

Power Dissipation in  $R_{GND}$  (when  $V_{CC}\mbox{-}0\mbox{:}$  during reverse battery situations) is:

#### $P_D = (-V_{CC})^2/R_{GND}$

This resistor can be shared amongst several different HSD. Please note that the value of this resistor should be calculated with formula (1) where  $I_{S(on)max}$  becomes the sum of the maximum on-state currents of the different devices.

Please note that if the microprocessor ground is not common with the device ground then the  $R_{GND}$  will produce a shift ( $I_{S(on)max} * R_{GND}$ ) in the input thresholds and the status output values. This shift will vary depending on many devices are ON in the case of several high side drivers sharing the same  $R_{GND}$ .

If the calculated power dissipation leads to a large resistor or several devices have to share the same resistor then the ST suggests to utilize Solution 2 (see below).

Solution 2: A diode (D<sub>GND</sub>) in the ground line.

A resistor  $(R_{GND}=1k\Omega)$  should be inserted in parallel to  $D_{GND}$  if the device will be driving an inductive load.

This small signal diode can be safely shared amongst several different HSD. Also in this case, the presence of

the ground network will produce a shift (j600mV) in the input threshold and the status output values if the microprocessor ground is not common with the device ground. This shift will not vary if more than one HSD shares the same diode/resistor network.

Series resistor in INPUT and STATUS lines are also required to prevent that, during battery voltage transient, the current exceeds the Absolute Maximum Rating.

Safest configuration for unused INPUT and STATUS pin is to leave them unconnected.

#### LOAD DUMP PROTECTION

 $D_{ld}$  is necessary (Voltage Transient Suppressor) if the load dump peak voltage exceeds  $V_{CC}$  max DC rating. The same applies if the device will be subject to transients on the  $V_{CC}$  line that are greater than the ones shown in the ISO T/R 7637/1 table.

#### $\mu$ C I/Os PROTECTION:

If a ground protection network is used and negative transients are present on the V<sub>CC</sub> line, the control pins will be pulled negative. ST suggests to insert a resistor (R<sub>prot</sub>) in line to prevent the  $\mu$ C I/Os pins to latch-up.

The value of these resistors is a compromise between the leakage current of  $\mu C$  and the current required by the HSD I/Os (Input levels compatibility) with the latch-up limit of  $\mu C$  I/Os.

 $\label{eq:VCCpeak} $$ VCCpeak/Ilatchup \leq R_{prot} \leq (V_{OH\mu C} - V_{IH} - V_{GND}) / I_{IHmax}$ Calculation example: $$$ 

For V<sub>CCpeak</sub>= - 100V and I<sub>latchup</sub>  $\ge$  20mA; V<sub>OHµC</sub>  $\ge$  4.5V 5k $\Omega \le R_{prot} \le 65k\Omega$ .

Recommended  $R_{prot}$  value is  $10k\Omega$ .



### **OPEN LOAD DETECTION IN OFF STATE**

Off state open load detection requires an external pull-up resistor ( $R_{PU}$ ) connected between OUTPUT pin and a positive supply voltage ( $V_{PU}$ ) like the +5V line used to supply the microprocessor.

The external resistor has to be selected according to the following requirements:

1) no false open load indication when load is connected: in this case we have to avoid  $V_{OUT}$  to be higher than  $V_{Olmin}$ ; this results in the following condition

 $V_{OUT}=(V_{PU}/(R_L+R_{PU}))R_L < V_{Olmin.}$ 

#### Figure 9. Open Load detection in off state

2) no misdetection when load is disconnected: in this case the V<sub>OUT</sub> has to be higher than V<sub>OLmax</sub>; this results in the following condition  $R_{PU}$ <(V<sub>PU-</sub>V<sub>OLmax</sub>)/ $I_{L(off2)}$ .

Because  $I_{s(OFF)}$  may significantly increase if  $V_{out}$  is pulled high (up to several mA), the pull-up resistor  $R_{PU}$  should be connected to a supply that is switched OFF when the module is in standby.

The values of  $V_{OLmin},\,V_{OLmax}$  and  $I_{L(off2)}$  are available in the Electrical Characteristics section.

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## PowerSSO-12 Thermal Data

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#### Figure 10. PowerSSO-12 PC Board









Figure 12. PowerSSO-12 Thermal Impedance Junction Ambient Single Pulse





# Pulse calculation formula

$$\begin{split} Z_{TH\delta} \ &= \ R_{TH} \cdot \delta + Z_{THtp}(1-\delta) \\ \text{where} \quad & \delta \ &= \ t_p / T \end{split}$$

## Table 14. Thermal Parameter

Area/island (cm <sup>2</sup> )	Footprint	8
R1/R7 (°C/W)	0.1	
R2/R3/R8 (°C/W)	1.5	
R4 (°C/W)	8	
R5 (°C/W)	28	18
R6 (°C/W)	30	22
C1/C7 (W.s/°C)	0.0001	
C2/C8 (W.s/°C)	0.0007	
C3 (W.s/°C)	0.015	
C4 (W.s/°C)	0.1	
C5 (W.s/°C)	0.15	0.017
C6 (W.s/°C)	3	5

## PACKAGE MECHANICAL

Symbol	millimeters			
	Min	Тур	Max	
А	1.250		1.620	
A1	0.000		0.100	
A2	1.100		1.650	
В	0.230		0.410	
С	0.190		0.250	
D	4.800		5.000	
E	3.800		4.000	
е		0.800		
Н	5.800		6.200	
h	0.250		0.500	
L	0.400		1.270	
k	0°		80	
Х	1.900		2.500	
Y	3.600		4.200	
ddd			0.100	

#### Table 15. PowerSSO-12<sup>™</sup> Mechanical Data





### **REVISION HISTORY**

## Table 16. Revision History

Date	Revision	Description of Changes
Oct. 2004	1	- First Issue
Nov. 2004	2	- PowerSSO-12 Thermal Charact. insertion
Nov. 2004	3	- PC Board copper area correction
Nov. 2004	4	- Thermal data correction.

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